

FORM 15 U.S. Department of Commerce Patent & Trademark Office INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	Attorney Docket No. 218TG/48722	Serial No. 09/524,755
	Applicant: Peter HEINRICH et al.	
	Filing Date March 13, 2000	Group

U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
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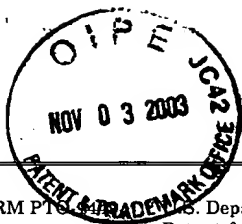
FOREIGN PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Country	Class	Sub-Class	TRANSLATION	
							Yes	No
	AK							
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		
SCC	AQ	VII Finnish Conference on Physics in Industry, Nov. 1-2, 1995, Tampere, Finland entitled "Real-Time Optical Spray Pattern Diagnostics for Thermal Spraying" by T. Lehtinen et al.
SCC	AR	Proceedings of the XXX Annual Conference of the Finnish Physical Society entitled "In-Flight Particle Visualisation in Thermal Plasma Spraying Using an Intensified CCD Camera" by T. Lehtinen et al.
SCC	AS	Proceedings of the XXXI Annual Conference of the Finnish Physical Societ, March 13-15, 1997, Helsinki, Finland entitled "In-Flight Particle Concentration Measurements in Thermal Plasma Spraying Using a CCD Camera by T. Lehtinen et al.

EXAMINER <i>Sheel Choren</i>	DATE CONSIDERED <i>4/8/04</i>
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See	AQ	Optics Day '97 - Proceedings Finnish Optical Society Tampere University of Technology, Feb. 21, 1997, Tampere, Finland entitled "Optical Spray Pattern Diagnostics for Thermal Spraying by T. Lehtinen et al.
	AR	
	AS	

EXAMINER *Sheel Chana*DATE CONSIDERED *4/8/04*

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